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| Notice of References Cited | Application/Control No. 10/759,696 | | Applicant(s)/Patent Under Reexamination YOUNG ET AL. | |
| | Examiner Brian P. Whipple | | Art Unit 2152 | Page 1 of 1 |

U.S. PATENT DOCUMENTS

| * | | Document Number Country Code-Number-Kind Code | Date MM-YYYY | Name | Classification |
|---|---|--|-----------------|----------------|----------------|
| * | A | US-6,269,253 B1 | 07-2001 | Maegawa et al. | 455/552.1 |
| * | B | US-6,327,268 B1 | 12-2001 | Sipila, Tuomo | 370/467 |
| * | C | US-6,349,205 B1 | 02-2002 | Fang et al. | 455/419 |
| * | D | US-2002/0147008 A1 | 10-2002 | Kallio, Janne | 455/426 |
| * | E | US-6,877,023 B1 | 04-2005 | Maffeis et al. | 709/202 |
| | F | US- | | | |
| | G | US- | | | |
| | H | US- | | | |
| | I | US- | | | |
| | J | US- | | | |
| | K | US- | | | |
| | L | US- | | | |
| | M | US- | | | |

FOREIGN PATENT DOCUMENTS

| * | | Document Number Country Code-Number-Kind Code | Date MM-YYYY | Country | Name | Classification |
|---|---|--|-----------------|---------|------|----------------|
| | N | | | | | |
| | O | | | | | |
| | P | | | | | |
| | Q | | | | | |
| | R | | | | | |
| | S | | | | | |
| | T | | | | | |

NON-PATENT DOCUMENTS

| * | | Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages) |
|---|---|---|
| | U | |
| | V | |
| | W | |
| | X | |

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